Taiwan Test Industry Session:
Value Added Testing in the New Millennium

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In the last two decades of the 20th century, the integrated circuit (IC) industry has prolonged and redefined Taiwan Economic Miracle. The relay has passed from OEM to IDM then to the foundry services. With the strong supports from the foundry and manufacturing sectors, the energetic and creative design sector has seen an unsurpassed opportunity in the new Millennium. The design sector will continue the trend and create a new horizon. The shift in the paradigm will have a significant impact on the test sector. In the Taiwan Test Industry Session, we will discuss how the test sector shall react, what the emerging technologies are, and what the new business protocol should be. We have invited distinguished members from designer, test, and ATE sectors to express their inside views.

The experts from design sectors will present their problems and requirements in the deep sub-micron circuit testing. The expert from the test sectors will present their current capability and technology roadmap regarding the technical concerns. Finally, ATE vendors will showcase their advanced machine in the New Millennium to tackle the problems. Technology wise, the testing of System on Chip, System in Package, mixed signal, RF, and signal integrity are some of the issues that will be discussed. Infrastructure wise, the protocol for the technical cooperation on the test development in the circuit design stage and the model for the business operation in the final test stage are the focus of the presentations.